Statistics for Particle Physics

Lecture 2: Statistical Tests

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Outline

Lecture1: Fundamentals

Probability

Random variables, pdfs

Lecture 2: Statistical tests

Formalism of frequentist tests

Comments on multivariate methods (brief)

p-values

Discovery and limits

Lecture 3: Parameter estimation

Properties of estimators

Maximum likelihood

Frequentist statistical tests

Consider a hypothesis H_0 and alternative H_1.

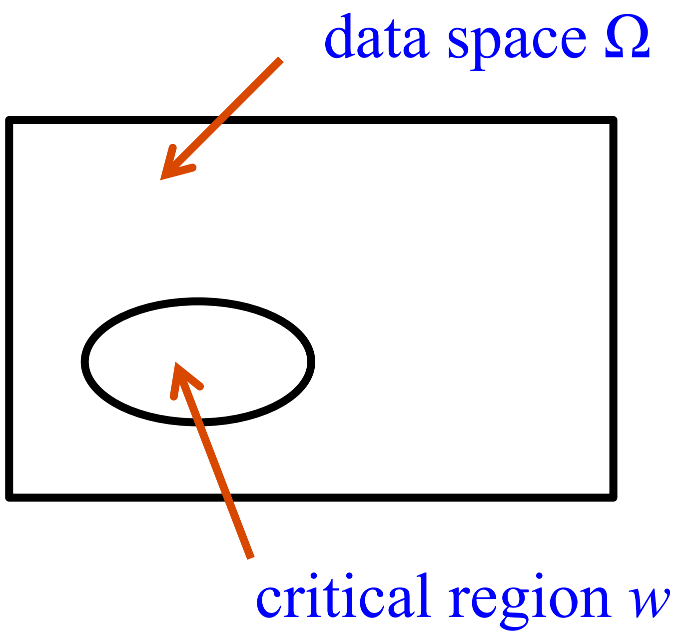
A test of H_0 is defined by specifying a critical region w of the data space such that there is no more than some (small) probability α, assuming H_0 is correct, to observe the data there, i.e.,

$$P(x \in w \mid H_0) \leq \alpha$$

Need inequality if data are discrete.

α is called the size or significance level of the test.

If x is observed in the critical region, reject H_0.

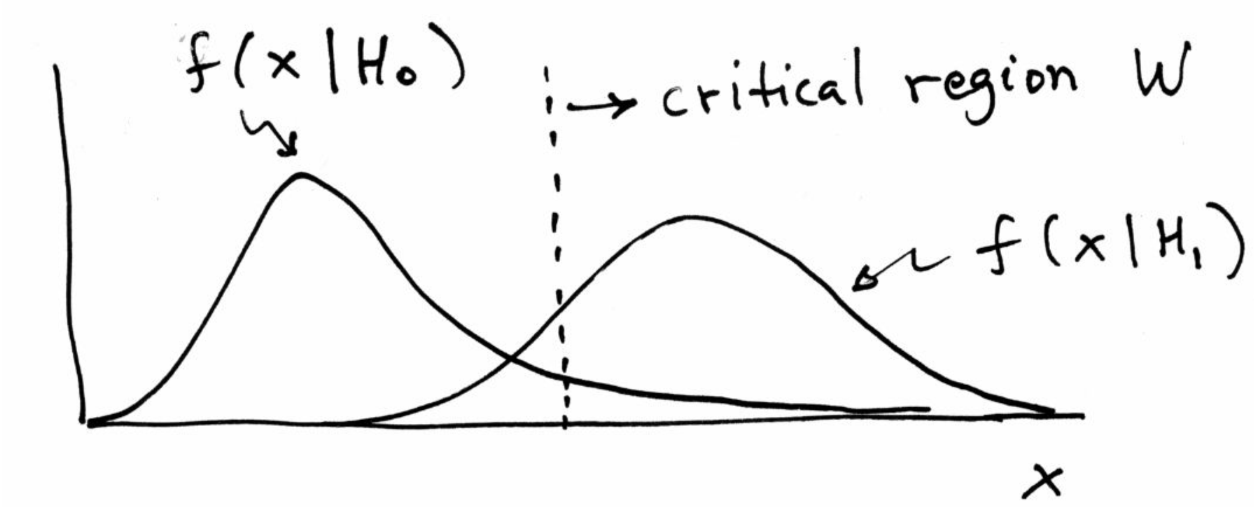


Definition of a test (2)

But in general there are an infinite number of possible critical regions that give the same significance level α.

So the choice of the critical region for a test of H_0 needs to take into account the alternative hypothesis H_1.

Roughly speaking, place the critical region where there is a low probability to be found if H_0 is true, but high if H_1 is true:



Type-I, Type-II errors

Rejecting the hypothesis H_0 when it is true is a Type-I error.

The maximum probability for this is the size of the test:

$$P(x \in W \mid H_0) \leq \alpha$$

But we might also accept H_0 when it is false, and an alternative H_1 is true.

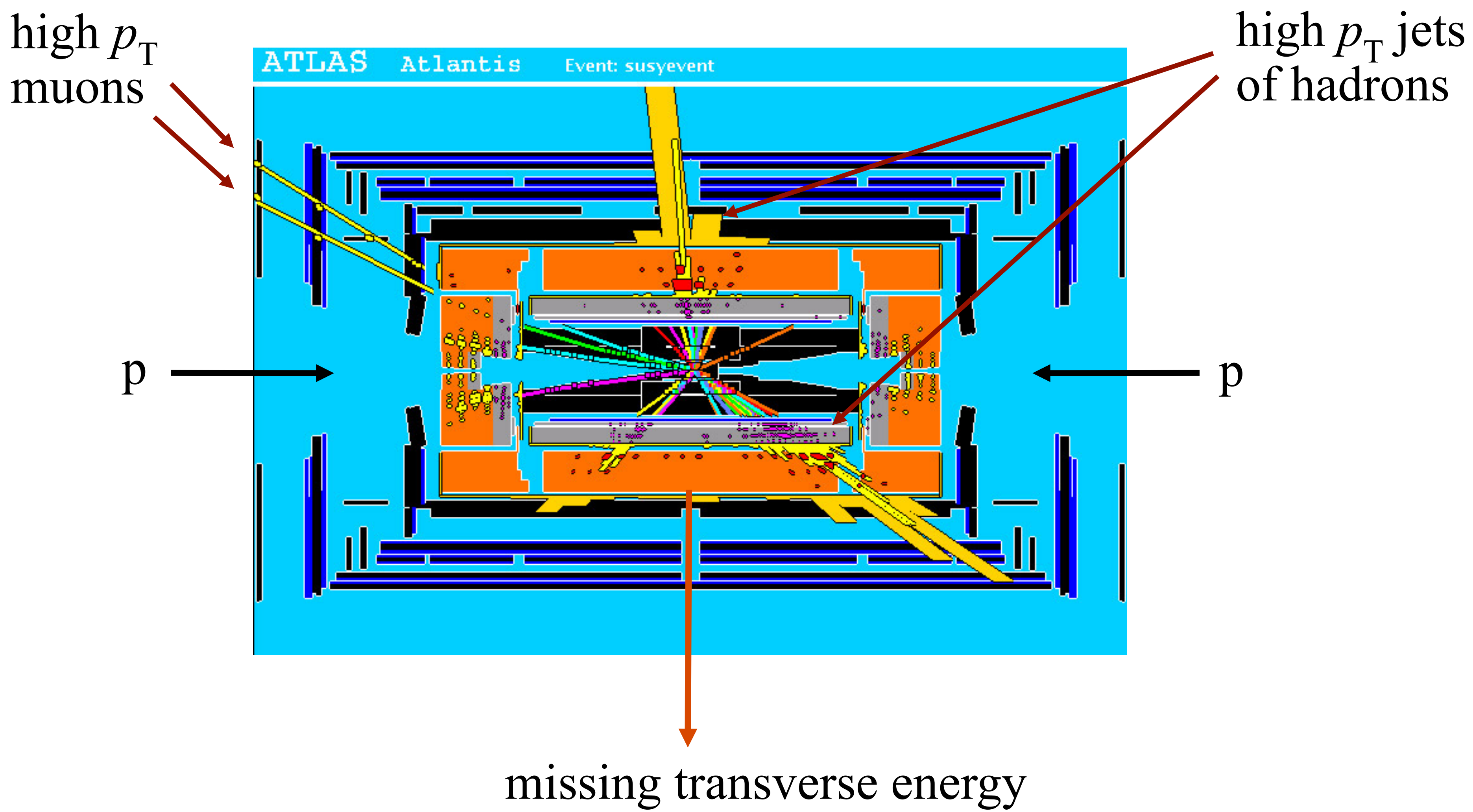
This is called a Type-II error, and occurs with probability

$$P(x \in S - W \mid H_1) = \beta$$

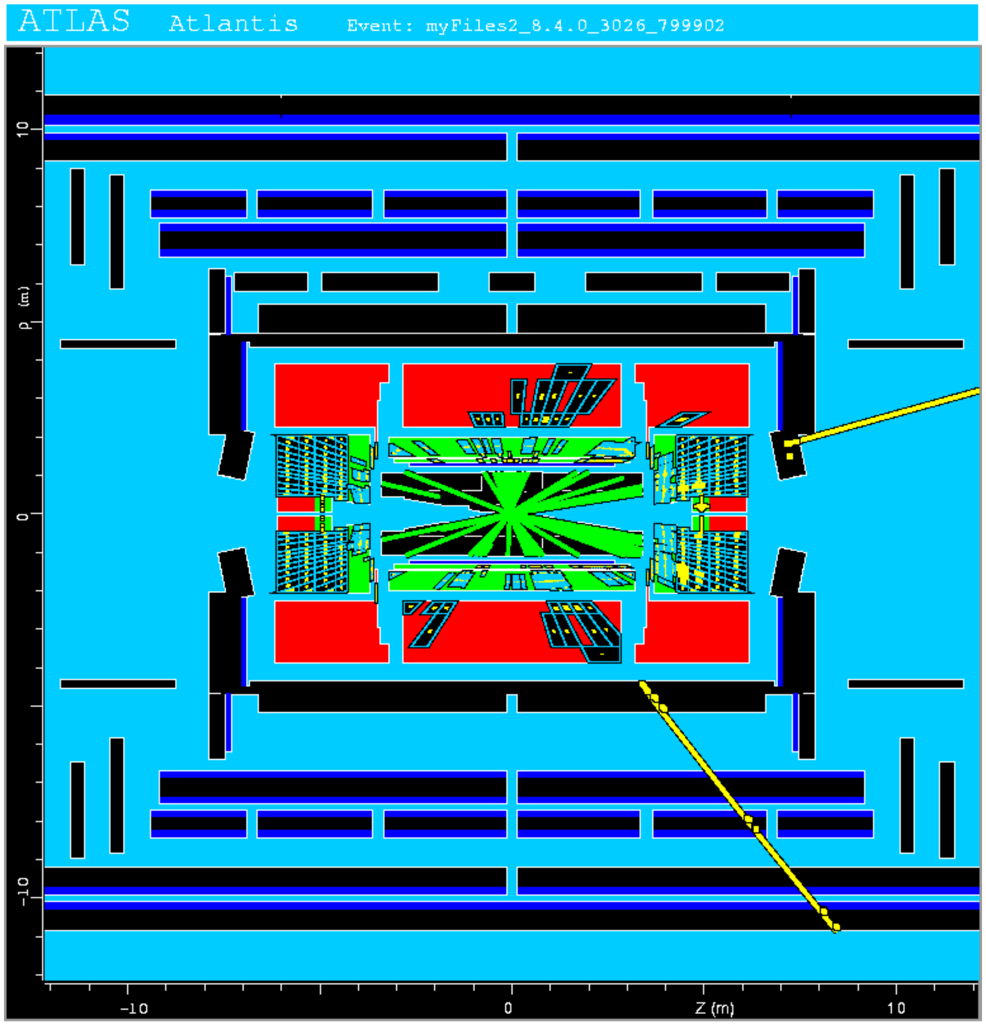
One minus this is called the power of the test with respect to the alternative H_1:

$$\text{Power} = 1 - \beta$$

A simulated SUSY event



Background events



This event from Standard Model ttbar production also has high p_T jets and muons, and some missing transverse energy.

→ can easily mimic a SUSY event.

Physics context of a statistical test

Event Selection: the event types in question are both known to exist.

Example: separation of different particle types (electron vs muon) or known event types (ttbar vs QCD multijet).
E.g. test H_0 : event is background vs. H_1 : event is signal.
Use selected events for further study.

Search for New Physics: the null hypothesis is

H_0 : all events correspond to Standard Model (background only),

and the alternative is

H_1 : events include a type whose existence is not yet established (signal plus background)

Many subtle issues here, mainly related to the high standard of proof required to establish presence of a new phenomenon. The optimal statistical test for a search is closely related to that used for event selection.

Statistical tests for event selection

Suppose the result of a measurement for an individual event is a collection of numbers $\vec{x} = (x_1, \ldots, x_n)$

x_1 = number of muons,

x_2 = mean p_{T} of jets,

x_3 = missing energy, ...

$\vec{x}$ follows some n-dimensional joint pdf, which depends on the type of event produced, i.e., was it

$$\mathrm{pp} \rightarrow t\bar{t} \ , \quad \mathrm{pp} \rightarrow \tilde{g}\tilde{g} \ , \ldots$$

For each reaction we consider we will have a hypothesis for the pdf of $\vec{x}$, e.g., $f(\vec{x}|H_0)$, $f(\vec{x}|H_1)$, etc.

E.g. call H_0 the background hypothesis (the event type we want to reject); H_1 is signal hypothesis (the type we want).

Selecting events

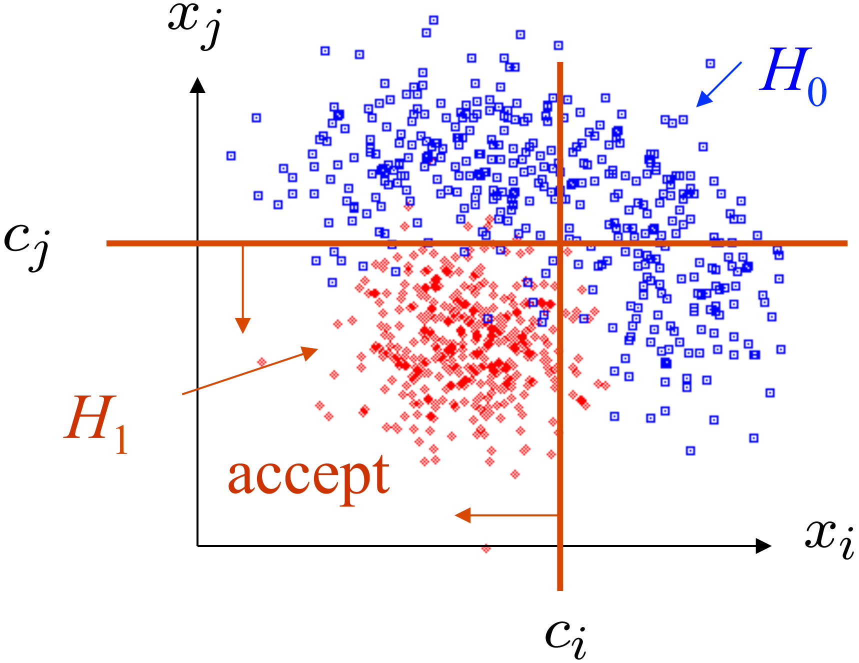
Suppose we have a data sample with two kinds of events, corresponding to hypotheses H_0 and H_1 and we want to select those of type H_1.

Each event is a point in $\vec{x}$ space. What 'decision boundary' should we use to accept/reject events as belonging to event types H_0 or H_1?

Perhaps select events with 'cuts':

$$x_i < c_i$$

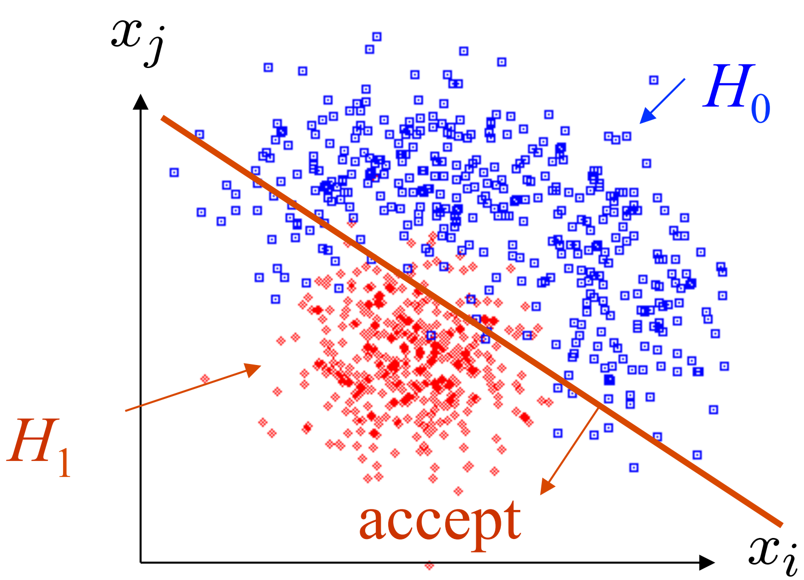
$$x_j < c_j$$



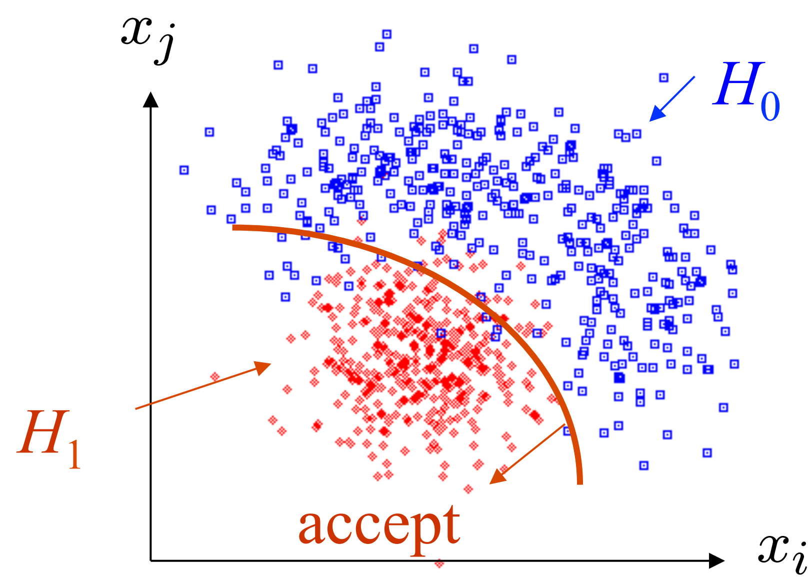
Other ways to select events

Or maybe use some other sort of decision boundary:

linear



or nonlinear



How can we do this in an 'optimal' way?

Test statistics

The boundary of the critical region for an n-dimensional data space $\boldsymbol{x} = (x_1,\dots, x_n)$ can be defined by an equation of the form

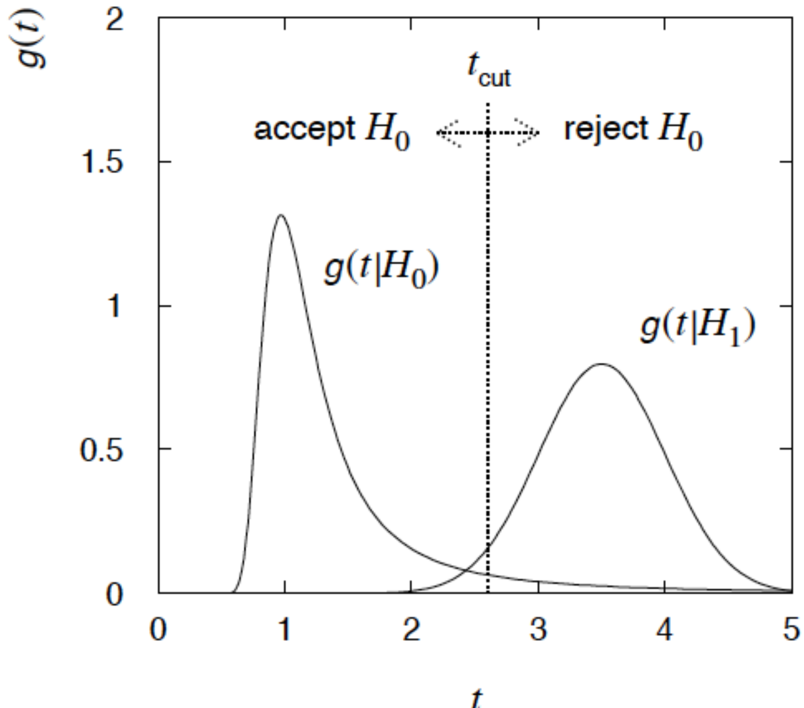
$$t(x_1,\dots,x_n) = t_{\rm cut}$$

where $t(x_1,\dots, x_n)$ is a scalar test statistic.

We can work out the pdfs $g(t|H_0),\ g(t|H_1),\ \dots$

Decision boundary is now a single 'cut' on t, defining the critical region.

So for an n-dimensional problem we have a corresponding 1-d problem.



Test statistic based on likelihood ratio

How can we choose a test's critical region in an 'optimal way'?

Neyman-Pearson lemma states:

To get the highest power for a given significance level in a test of H_0, (background) versus H_1, (signal) the critical region should have

$$\frac{f(\mathbf{x}|H_1)}{f(\mathbf{x}|H_0)} > c$$

inside the region, and $\leq c$ outside, where c is a constant chosen to give a test of the desired size.

Equivalently, optimal scalar test statistic is

$$\boxed{t(\mathbf{x}) = \frac{f(\mathbf{x}|H_1)}{f(\mathbf{x}|H_0)}}$$

N.B. any monotonic function of this is leads to the same test.

Classification viewed as a statistical test

Probability to reject H_0 if true (type I error): $\alpha = \int_W f(\mathbf{x}|H_0) d\mathbf{x}$

α = size of test, significance level, false discovery rate

Probability to accept H_0 if H_1 true (type II error) $\beta = \int_{\overline{W}} f(\mathbf{x}|H_1) d\mathbf{x}$

$1 - \beta$ = power of test with respect to H_1

Equivalently if e.g. H_0 = background, H_1 = signal, use efficiencies:

$$\varepsilon_{\rm b} = \int_W f(\mathbf{x}|H_0) = \alpha$$

$$\varepsilon_{\rm s} = \int_W f(\mathbf{x}|H_1) = 1 - \beta = \text{power}$$

Purity / misclassification rate

Consider the probability that an event of signal (s) type classified correctly (i.e., the event selection purity),

Use Bayes' theorem:

Here W is signal region

$\varepsilon_{\rm s}$

prior probability

$$P(\mathrm{s}|\mathbf{x} \in W) = \frac{P(\mathbf{x} \in W|\mathrm{s})P(\mathrm{s})}{P(\mathbf{x} \in W|\mathrm{s})P(\mathrm{s}) + P(\mathbf{x} \in W|\mathrm{b})P(\mathrm{b})}$$

$\varepsilon_{\rm b}$

posterior probability = signal purity

= 1 – signal misclassification rate

Note purity depends on the prior probability for an event to be signal or background as well as on s/b efficiencies.

Neyman-Pearson doesn't usually help

We usually don't have explicit formulae for the pdfs $f(\boldsymbol{x}|\mathrm{s})$, $f(\boldsymbol{x}|\mathrm{b})$, so for a given $\boldsymbol{x}$ we can't evaluate the likelihood ratio

$$t(\mathbf{x}) = \frac{f(\mathbf{x}|s)}{f(\mathbf{x}|b)}$$

Instead we may have Monte Carlo models for signal and background processes, so we can produce simulated data:

$$\text{generate } \boldsymbol{x} \sim f(\boldsymbol{x}|\mathrm{s}) \quad \rightarrow \quad \boldsymbol{x}_1, \ldots, \boldsymbol{x}_N$$

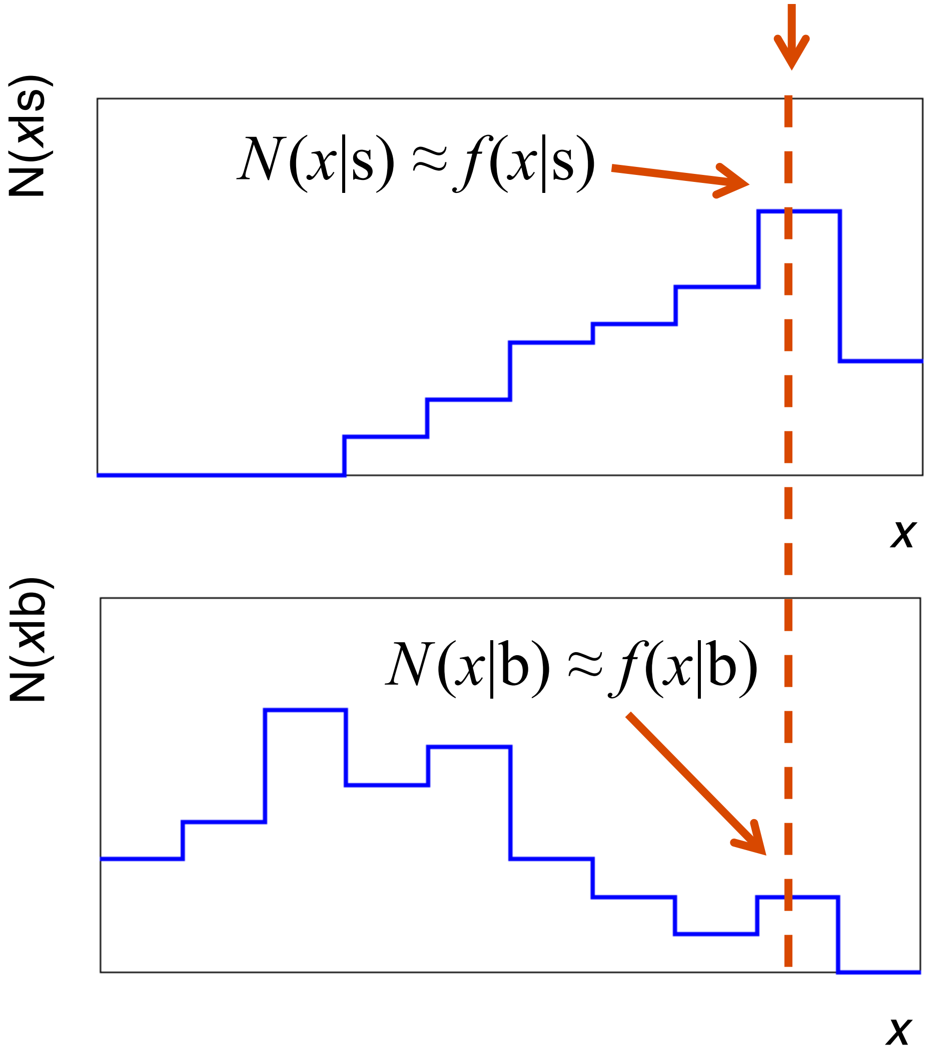
$$\text{generate } \boldsymbol{x} \sim f(\boldsymbol{x}|\mathrm{b}) \quad \rightarrow \quad \boldsymbol{x}_1, \ldots, \boldsymbol{x}_N$$

This gives samples of "training data" with events of known type.

Can be expensive (1 fully simulated LHC event ~ 1 CPU minute).

Approximate LR from histograms

Want $t(x) = f(x|\mathrm{s})/f(x|\mathrm{b})$ for x here



One possibility is to generate MC data and construct histograms for both signal and background.

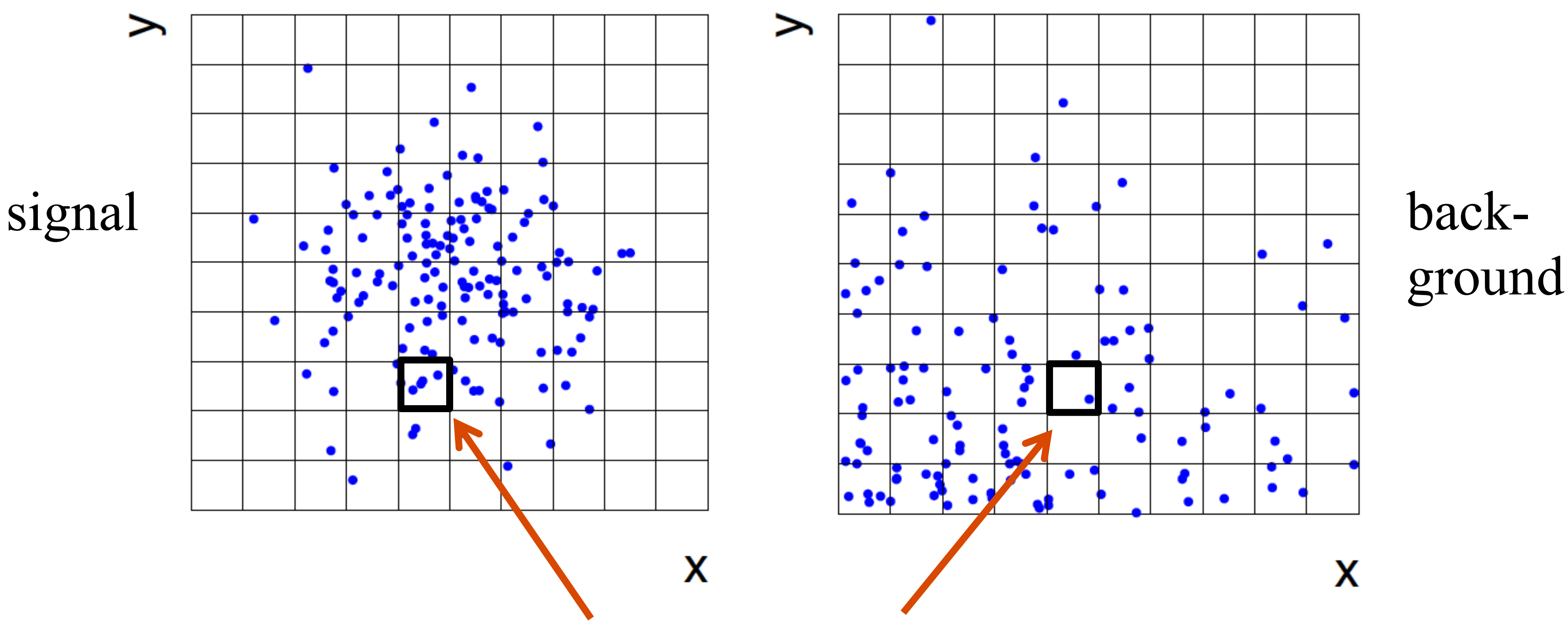
Use (normalized) histogram values to approximate LR:

$$t(x) \approx \frac{N(x|s)}{N(x|b)}$$

Can work well for single variable.

Approximate LR from 2D-histograms

Suppose problem has 2 variables. Try using 2-D histograms:



Approximate pdfs using $N(x,y|\mathrm{s})$, $N(x,y|\mathrm{b})$ in corresponding cells.

But if we want M bins for each variable, then in n-dimensions we have M^n cells; can't generate enough training data to populate.

→ Histogram method usually not usable for $n > 1$ dimension.

Strategies for multivariate analysis

Neyman-Pearson lemma gives optimal answer, but cannot be used directly, because we usually don't have $f(\boldsymbol{x}|\mathrm{s})$, $f(\boldsymbol{x}|\mathrm{b})$.

Histogram method with M bins for n variables requires that we estimate M^n parameters (the values of the pdfs in each cell), so this is rarely practical.

A compromise solution is to assume a certain functional form for the test statistic $t(\boldsymbol{x})$ with fewer parameters; determine them (using MC) to give best separation between signal and background.

Alternatively, try to estimate the probability densities $f(\boldsymbol{x}|\mathrm{s})$ and $f(\boldsymbol{x}|\mathrm{b})$ (with something better than histograms) and use the estimated pdfs to construct an approximate likelihood ratio.

Multivariate methods

Many new (and some old) methods:

- Fisher discriminant
- (Deep) neural networks
- Kernel density methods
- Support Vector Machines
- Decision trees
  - Boosting
  - Bagging

Resources on multivariate methods

C.M. Bishop, Pattern Recognition and Machine Learning, Springer, 2006

T. Hastie, R. Tibshirani, J. Friedman, The Elements of Statistical Learning, 2^{nd} ed., Springer, 2009

R. Duda, P. Hart, D. Stork, Pattern Classification, 2^{nd} ed., Wiley, 2001

A. Webb, Statistical Pattern Recognition, 2^{nd} ed., Wiley, 2002.

Ilya Narsky and Frank C. Porter, *Statistical Analysis Techniques in Particle Physics*, Wiley, 2014.

朱永生（编著），实验数据多元统计分析，科学出版社，北京，2009。

Software

Rapidly growing area of development – two important resources:

TMVA, Höcker, Stelzer, Tegenfeldt, Voss, Voss, physics/0703039

From **`tmva.sourceforge.net`**, also distributed with ROOT

Variety of classifiers

Good manual, widely used in HEP

scikit-learn

Python-based tools for Machine Learning

`scikit-learn.org`

Large user community

Testing significance / goodness-of-fit

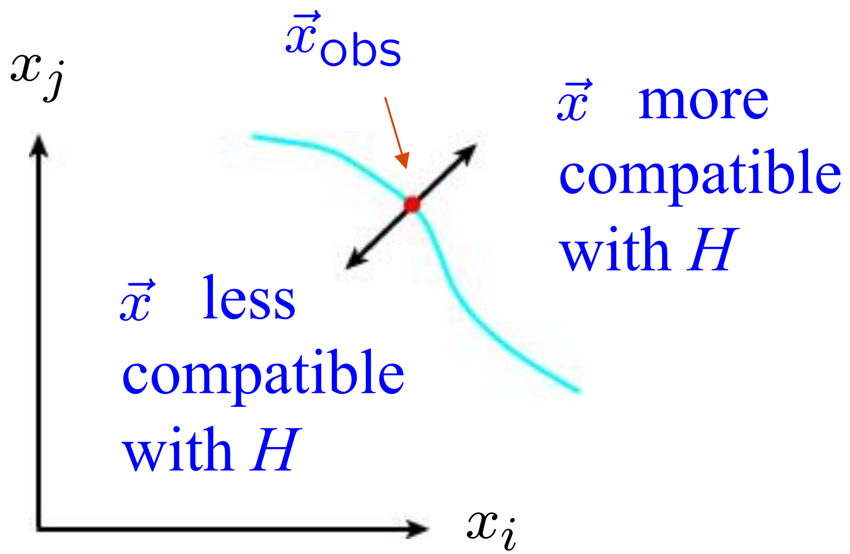
Suppose hypothesis H predicts pdf $f(\vec{x}|H)$ for a set of observations $\vec{x} = (x_1, \ldots, x_n)$.

We observe a single point in this space: $\vec{x}_{\mathrm{obs}}$

What can we say about the validity of H in light of the data?

Decide what part of the data space represents less compatibility with H than does the point $\vec{x}_{\mathrm{obs}}$.

Note – "less compatible with H" means "more compatible with some alternative H' ".



p-values

Express ‘goodness-of-fit’ by giving the *p*-value for *H*:

p = probability, under assumption of *H*, to observe data with equal or lesser compatibility with *H* relative to the data we got.

This is not the probability that *H* is true!

In frequentist statistics we don’t talk about *P*(*H*) (unless *H* represents a repeatable observation). In Bayesian statistics we do; use Bayes’ theorem to obtain

$$P(H|\vec{x}) = \frac{P(\vec{x}|H)\pi(H)}{\int P(\vec{x}|H)\pi(H)\,dH}$$

where $\pi(H)$ is the prior probability for *H*.

For now stick with the frequentist approach;
result is *p*-value, regrettably easy to misinterpret as *P*(*H*).

p-value example: testing whether a coin is 'fair'

Probability to observe n heads in N coin tosses is binomial:

$$P(n; p, N) = \frac{N!}{n!(N-n)!} p^n (1-p)^{N-n}$$

Hypothesis H: the coin is fair ($p = 0.5$).

Suppose we toss the coin $N = 20$ times and get $n = 17$ heads.

Region of data space with equal or lesser compatibility with H relative to $n = 17$ is: $n = 17, 18, 19, 20, 0, 1, 2, 3$. Adding up the probabilities for these values gives:

$$P(n = 0, 1, 2, 3, 17, 18, 19, \text{ or } 20) = 0.0026 \ .$$

i.e. $p = 0.0026$ is the probability of obtaining such a bizarre result (or more so) 'by chance', under the assumption of H.

Distribution of the p-value

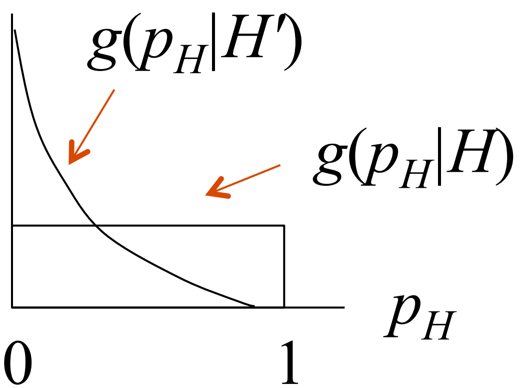
The p-value is a function of the data, and is thus itself a random variable with a given distribution. Suppose the p-value of H is found from a test statistic $t(\boldsymbol{x})$ as

$$p_H = \int_t^{\infty} f(t'|H)\,dt'$$

The pdf of p_H under assumption of H is

$$g(p_H|H) = \frac{f(t|H)}{|\partial p_H/\partial t|} = \frac{f(t|H)}{f(t|H)} = 1 \quad (0 \leq p_H \leq 1)$$

In general for continuous data, under assumption of H, $p_H \sim$ Uniform[0,1] and is concentrated toward zero for Some class of relevant alternatives.



Using a p-value to define test of H_0

One can show the distribution of the p-value of H, under assumption of H, is uniform in [0,1].

So the probability to find the p-value of H_0, p_0, less than α is

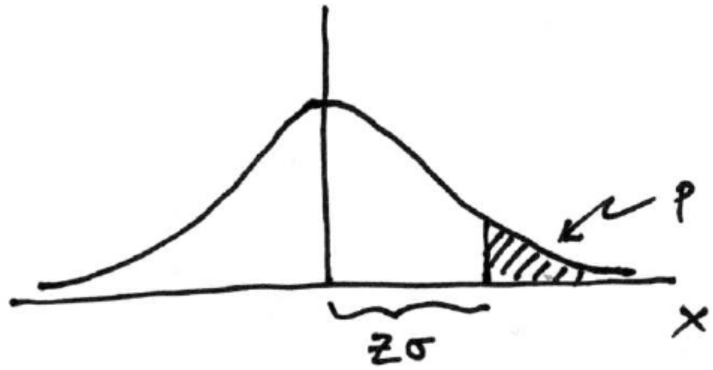
$$P(p_0 \leq \alpha | H_0) = \alpha$$

We can define the critical region of a test of H_0 with size α as the set of data space where $p_0 \leq \alpha$.

Formally the p-value relates only to H_0, but the resulting test will have a given power with respect to a given alternative H_1.

Significance from p-value

Often define significance Z as the number of standard deviations that a Gaussian variable would fluctuate in one direction to give the same p-value.



$$p = \int_Z^\infty \frac{1}{\sqrt{2\pi}} e^{-x^2/2}\, dx = 1 - \Phi(Z)$$

1 - TMath::Freq

$$Z = \Phi^{-1}(1-p)$$

TMath::NormQuantile

E.g. $Z = 5$ (a "5 sigma effect") corresponds to $p = 2.9 \times 10^{-7}$.

The Poisson counting experiment

Suppose we do a counting experiment and observe n events.

Events could be from *signal* process or from *background* – we only count the total number.

Poisson model:

$$P(n|s,b) = \frac{(s+b)^n}{n!} e^{-(s+b)}$$

s = mean (i.e., expected) # of signal events

b = mean # of background events

Goal is to make inference about s, e.g.,

test $s = 0$ (rejecting $H_0 \approx$ "discovery of signal process")

test all non-zero s (values not rejected = confidence interval)

In both cases need to ask what is relevant alternative hypothesis.

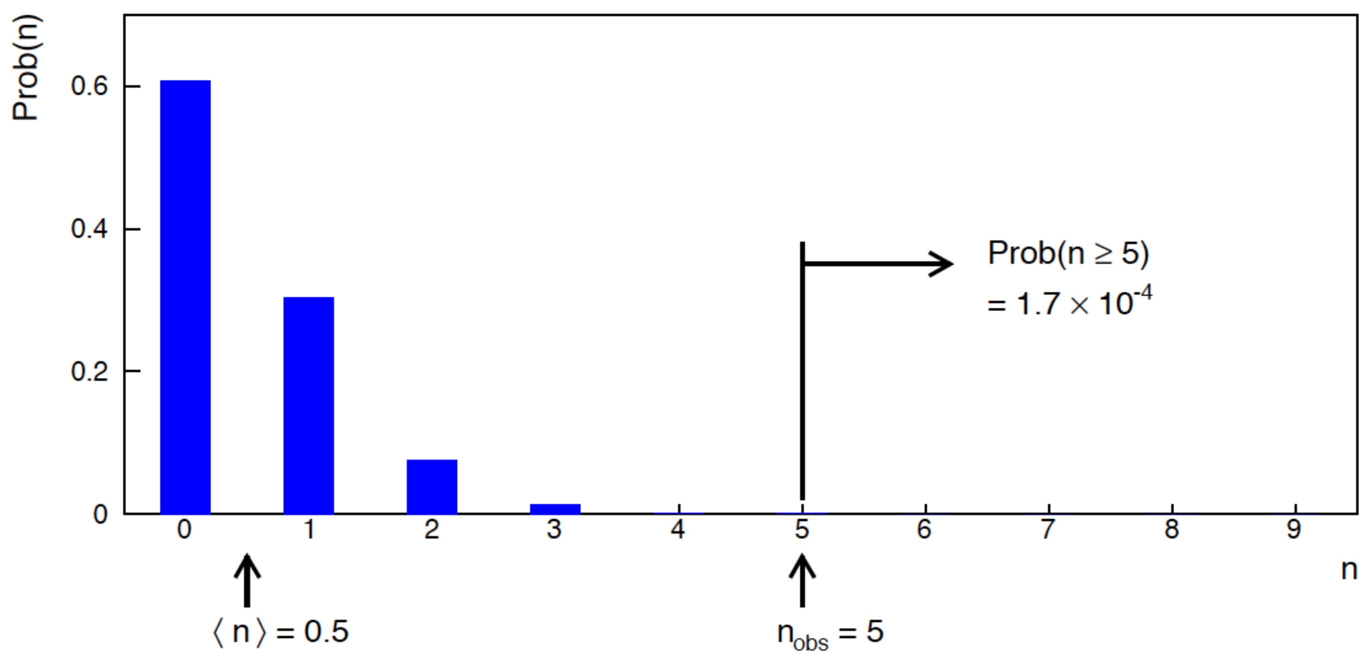
Poisson counting experiment: discovery p-value

Suppose $b = 0.5$ (known), and we observe $n_{\rm obs} = 5$.

Should we claim evidence for a new discovery?

Give p-value for hypothesis $s = 0$:

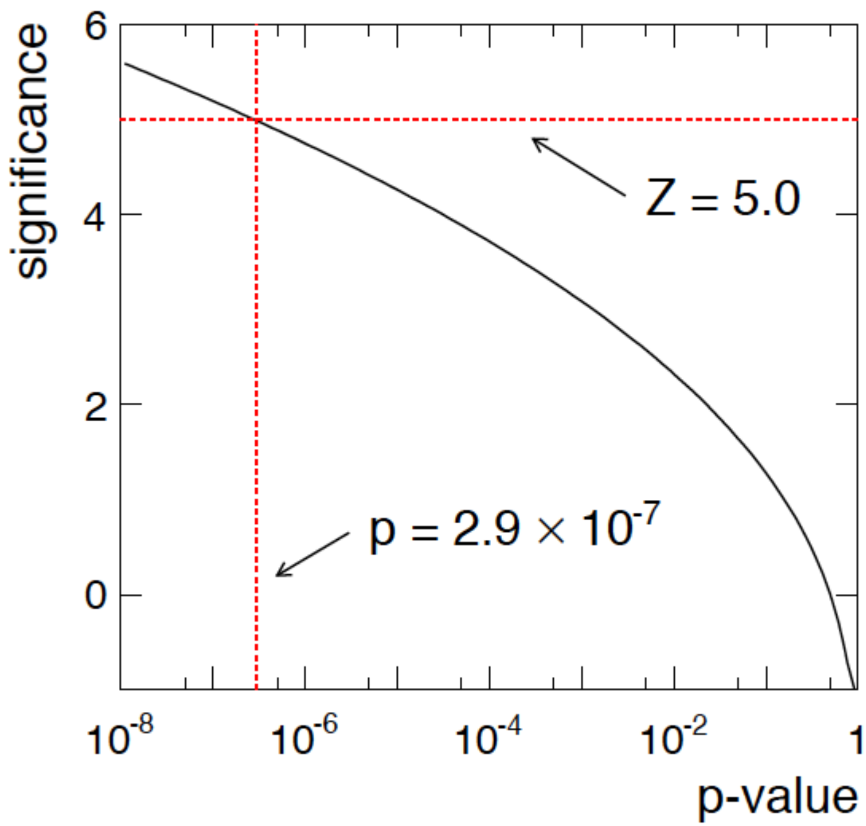
$$\begin{aligned} p\text{-value} &= P(n \geq 5; b = 0.5, s = 0) \\ &= 1.7 \times 10^{-4} \neq P(s = 0)! \end{aligned}$$



Poisson counting experiment: discovery significance

Equivalent significance for $p = 1.7 \times 10^{-4}$: $Z = \Phi^{-1}(1 - p) = 3.6$

Often claim discovery if $Z > 5$ ($p < 2.9 \times 10^{-7}$, i.e., a "5-sigma effect")



In fact this tradition should be revisited: p-value intended to quantify probability of a signal-like fluctuation assuming background only; not intended to cover, e.g., hidden systematics, plausibility signal model, compatibility of data with signal, "look-elsewhere effect" (~multiple testing), etc.

Confidence intervals by inverting a test

Confidence intervals for a parameter θ can be found by defining a test of the hypothesized value θ (do this for all θ):

Specify values of the data that are 'disfavoured' by θ (critical region) such that P(data in critical region) $\leq \alpha$ for a prespecified α, e.g., 0.05 or 0.1.

If data observed in the critical region, reject the value θ.

Now invert the test to define a confidence interval as:

set of θ values that would not be rejected in a test of size α (confidence level is $1 - \alpha$).

The interval will cover the true value of θ with probability $\geq 1 - \alpha$.

Equivalently, the parameter values in the confidence interval have p-values of at least α.

To find edge of interval (the "limit"), set $p_\theta = \alpha$ and solve for θ.

Frequentist upper limit on Poisson parameter

Consider again the case of observing $n \sim \text{Poisson}(s + b)$.

Suppose $b = 4.5$, $n_{\text{obs}} = 5$. Find upper limit on s at 95% CL.

When testing s values to find upper limit, relevant alternative is $s = 0$ (or lower s), so critical region at low n and p-value of hypothesized s is $P(n \leq n_{\text{obs}}; s, b)$.

Upper limit s_{up} at $\text{CL} = 1 - \alpha$ from setting $\alpha = p_s$ and solving for s:

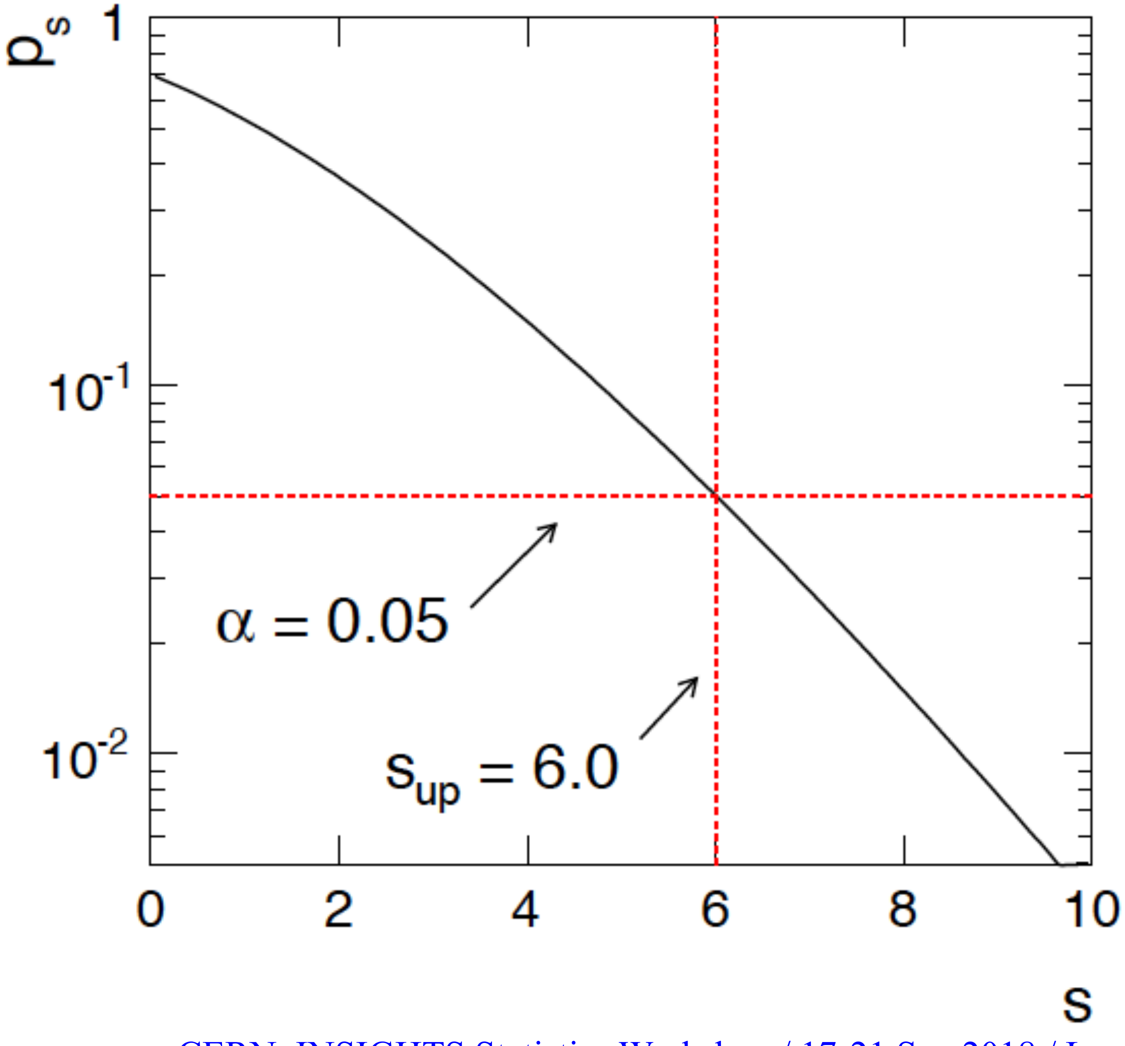
$$\alpha = P(n \leq n_{\text{obs}}; s_{\text{up}}, b) = \sum_{n=0}^{n_{\text{obs}}} \frac{(s_{\text{up}} + b)^n}{n!} e^{-(s_{\text{up}}+b)}$$

$$s_{\text{up}} = \frac{1}{2} F_{\chi^2}^{-1}(1 - \alpha; 2(n_{\text{obs}} + 1)) - b$$

$$= \frac{1}{2} F_{\chi^2}^{-1}(0.95; 2(5 + 1)) - 4.5 = 6.0$$

Frequentist upper limit on Poisson parameter

Upper limit $s_{\rm up}$ at CL = 1 – α found from $p_s = \alpha$.

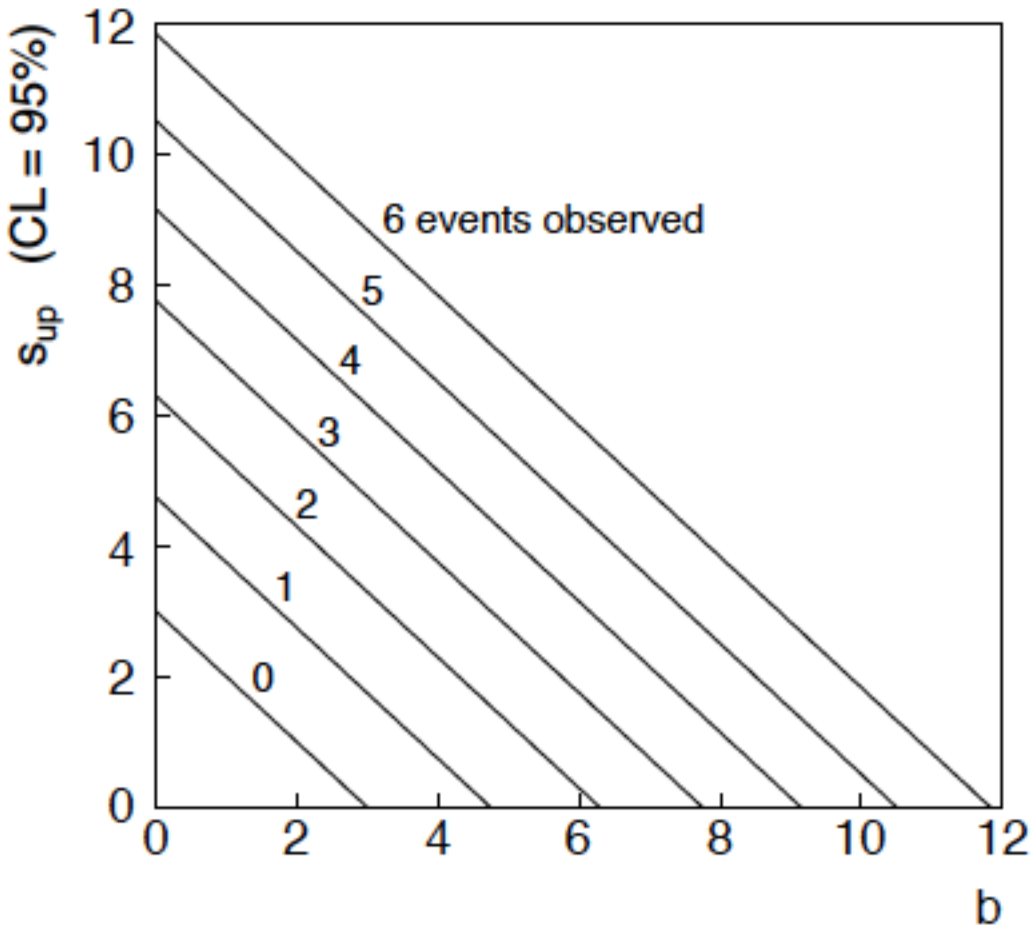


$n_{\rm obs} = 5$,

$b = 4.5$

$n \sim$ Poisson(s+b): frequentist upper limit on s

For low fluctuation of n formula can give negative result for s_{up}; i.e. confidence interval is empty.



Limits near a physical boundary

Suppose e.g. $b = 2.5$ and we observe $n = 0$.

If we choose CL = 0.9, we find from the formula for s_{up}

$$s_{\mathrm{up}} = -0.197 \quad (\mathrm{CL} = 0.90)$$

Physicist:

We already knew $s \geq 0$ before we started; can't use negative upper limit to report result of expensive experiment!

Statistician:

The interval is designed to cover the true value only 90% of the time — this was clearly not one of those times.

Not uncommon dilemma when testing parameter values for which one has very little experimental sensitivity, e.g., very small s.

Expected limit for $s = 0$

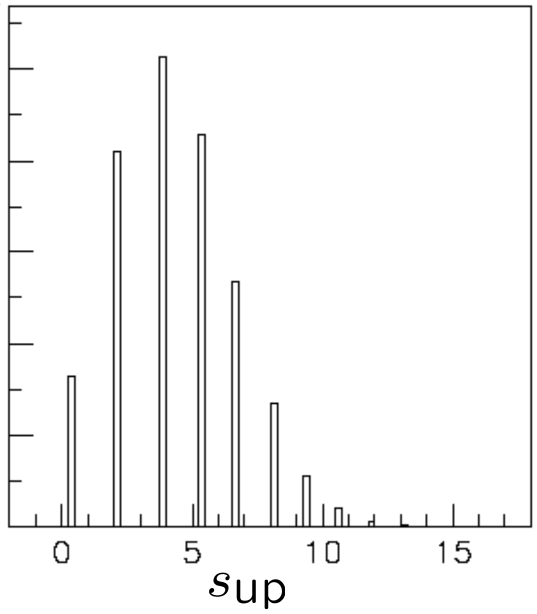
Physicist: I should have used CL = 0.95 — then $s_{up} = 0.496$

Even better: for CL = 0.917923 we get $s_{up} = 10^{-4}$!

Reality check: with $b = 2.5$, typical Poisson fluctuation in n is at least $\sqrt{2.5} = 1.6$. How can the limit be so low?

Look at the mean limit for the no-signal hypothesis ($s = 0$) (sensitivity).

Distribution of 95% CL limits with $b = 2.5$, $s = 0$.
Mean upper limit = 4.44



The Bayesian approach to limits

In Bayesian statistics need to start with 'prior pdf' $\pi(\theta)$, this reflects degree of belief about θ before doing the experiment.

Bayes' theorem tells how our beliefs should be updated in light of the data x:

$$p(\theta|x) = \frac{L(x|\theta)\pi(\theta)}{\int L(x|\theta')\pi(\theta')\,d\theta'} \propto L(x|\theta)\pi(\theta)$$

Integrate posterior pdf $p(\theta|\,x)$ to give interval with any desired probability content.

For e.g. $n \sim$ Poisson(s+b), 95% CL upper limit on s from

$$0.95 = \int_{-\infty}^{s_{\text{up}}} p(s|n)\,ds$$

Bayesian prior for Poisson parameter

Include knowledge that $s \geq 0$ by setting prior $\pi(s) = 0$ for $s < 0$.

Could try to reflect 'prior ignorance' with e.g.

$$\pi(s) = \begin{cases} 1 & s \geq 0 \\ 0 & \text{otherwise} \end{cases}$$

Not normalized but this is OK as long as $L(s)$ dies off for large s.

Not invariant under change of parameter — if we had used instead a flat prior for, say, the mass of the Higgs boson, this would imply a non-flat prior for the expected number of Higgs events.

Doesn't really reflect a reasonable degree of belief, but often used as a point of reference;

or viewed as a recipe for producing an interval whose frequentist properties can be studied (coverage will depend on true s).

Bayesian interval with flat prior for *s*

Solve to find limit s_{up}:

$$s_{\mathrm{up}} = \frac{1}{2} F_{\chi^2}^{-1}\left[p, 2(n+1)\right] - b$$

where

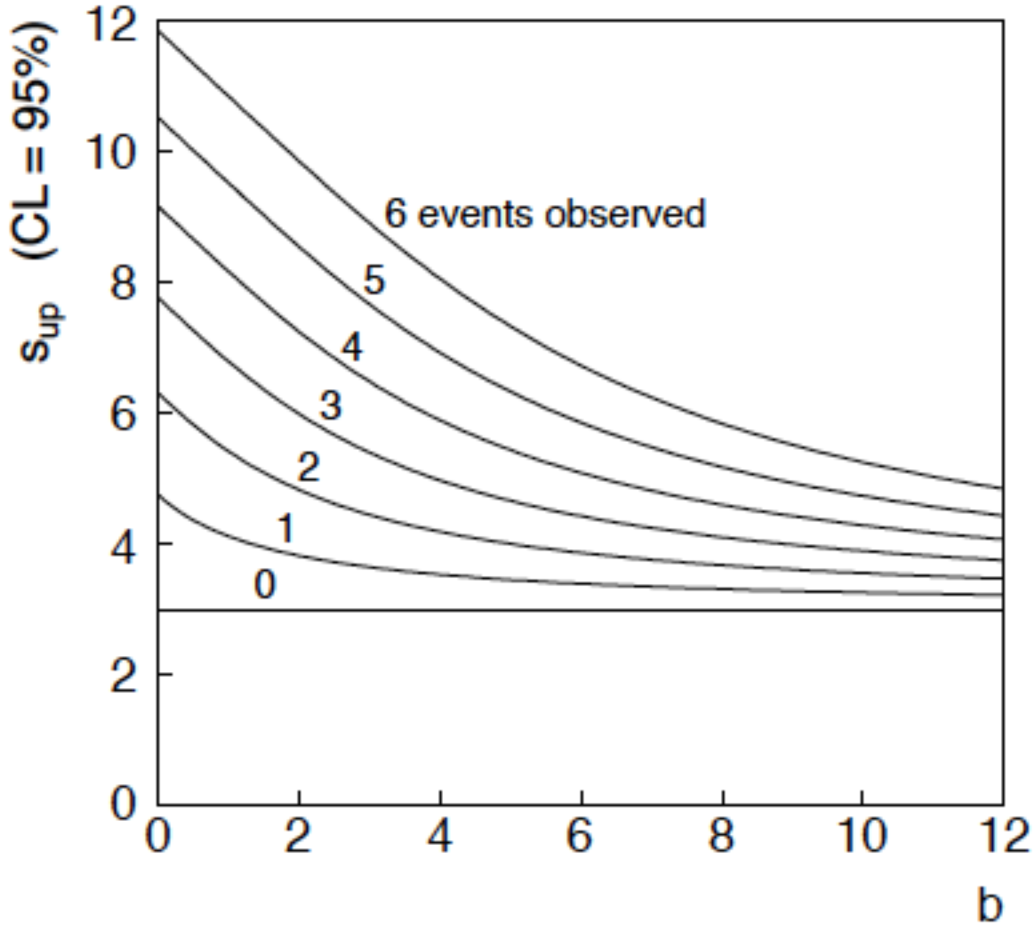
$$p = 1 - \alpha\left(1 - F_{\chi^2}\left[2b, 2(n+1)\right]\right)$$

For special case $b = 0$, Bayesian upper limit with flat prior numerically same as one-sided frequentist case ('coincidence').

Bayesian interval with flat prior for s

For $b > 0$ Bayesian limit is everywhere greater than the (one sided) frequentist upper limit.

Never goes negative. Doesn't depend on b if $n = 0$.



Extra slides

Priors from formal rules

Because of difficulties in encoding a vague degree of belief in a prior, one often attempts to derive the prior from formal rules, e.g., to satisfy certain invariance principles or to provide maximum information gain for a certain set of measurements.

Often called "objective priors"
Form basis of Objective Bayesian Statistics

The priors do not reflect a degree of belief (but might represent possible extreme cases).

In Objective Bayesian analysis, can use the intervals in a frequentist way, i.e., regard Bayes' theorem as a recipe to produce an interval with certain coverage properties.

Priors from formal rules (cont.)

For a review of priors obtained by formal rules see, e.g.,

Robert E. Kass and Larry Wasserman, *The Selection of Prior Distributions by Formal Rules*, J. Am. Stat. Assoc., Vol. 91, No. 435, pp. 1343-1370 (1996).

Formal priors have not been widely used in HEP, but there is recent interest in this direction, especially the reference priors of Bernardo and Berger; see e.g.

L. Demortier, S. Jain and H. Prosper, *Reference priors for high energy physics*, Phys. Rev. D 82 (2010) 034002, arXiv:1002.1111.

D. Casadei, *Reference analysis of the signal + background model in counting experiments*, JINST 7 (2012) 01012; arXiv:1108.4270.

Jeffreys' prior

According to *Jeffreys' rule*, take prior according to

$$\pi(\boldsymbol{\theta}) \propto \sqrt{\det(I(\boldsymbol{\theta}))}$$

where

$$I_{ij}(\boldsymbol{\theta}) = -E\left[\frac{\partial^2 \ln L(\boldsymbol{x}|\boldsymbol{\theta})}{\partial\theta_i \partial\theta_j}\right] = -\int \frac{\partial^2 \ln L(\boldsymbol{x}|\boldsymbol{\theta})}{\partial\theta_i \partial\theta_j} L(\boldsymbol{x}|\boldsymbol{\theta})\, d\boldsymbol{x}$$

is the Fisher information matrix.

One can show that this leads to inference that is invariant under a transformation of parameters.

For a Gaussian mean, the Jeffreys' prior is constant; for a Poisson mean μ it is proportional to $1/\sqrt{\mu}$.

Jeffreys' prior for Poisson mean

Suppose $n \sim$ Poisson(μ). To find the Jeffreys' prior for μ,

$$L(n|\mu) = \frac{\mu^n}{n!} e^{-\mu} \qquad \frac{\partial^2 \ln L}{\partial \mu^2} = -\frac{n}{\mu}$$

$$I = -E\left[\frac{\partial^2 \ln L}{\partial \mu^2}\right] = \frac{E[n]}{\mu^2} = \frac{1}{\mu}$$

$$\pi(\mu) \propto \sqrt{I(\mu)} = \frac{1}{\sqrt{\mu}}$$

So e.g. for $\mu = s + b$, this means the prior $\pi(s) \sim 1/\sqrt{(s + b)}$, which depends on b. But this is not designed as a degree of belief about s.

A simple example (2D)

Consider two variables, x_1 and x_2, and suppose we have formulas for the joint pdfs for both signal (s) and background (b) events (in real problems the formulas are usually not available).

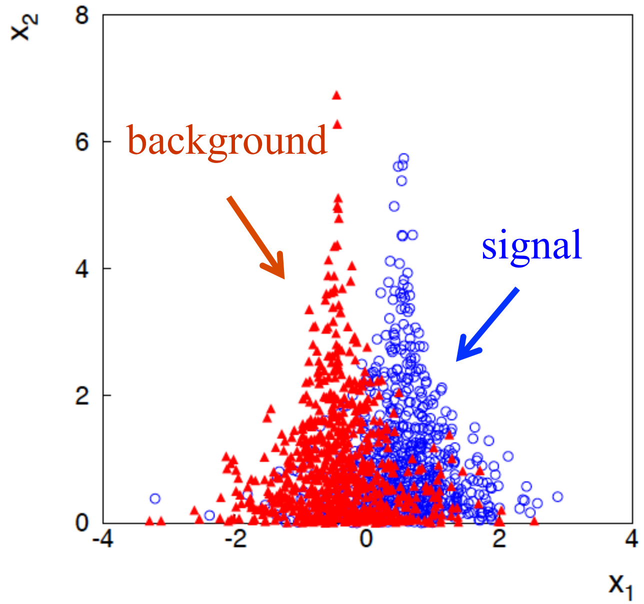
$f(x_1|x_2)$ ~ Gaussian, different means for s/b,
Gaussians have same σ, which depends on x_2,
$f(x_2)$ ~ exponential, same for both s and b,
$f(x_1, x_2) = f(x_1|x_2)\, f(x_2)$:

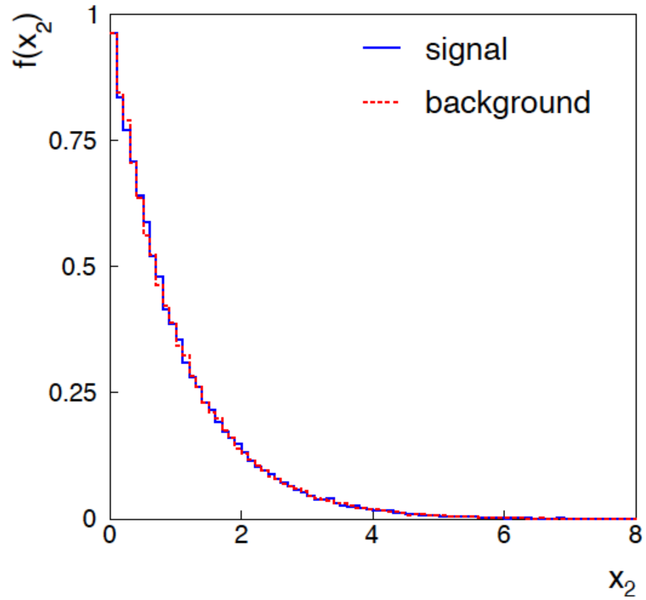
$$f(x_1, x_2|\mathrm{s}) = \frac{1}{\sqrt{2\pi}\sigma(x_2)} e^{-(x_1-\mu_\mathrm{s})^2/2\sigma^2(x_2)}\, \frac{1}{\lambda} e^{-x_2/\lambda}$$

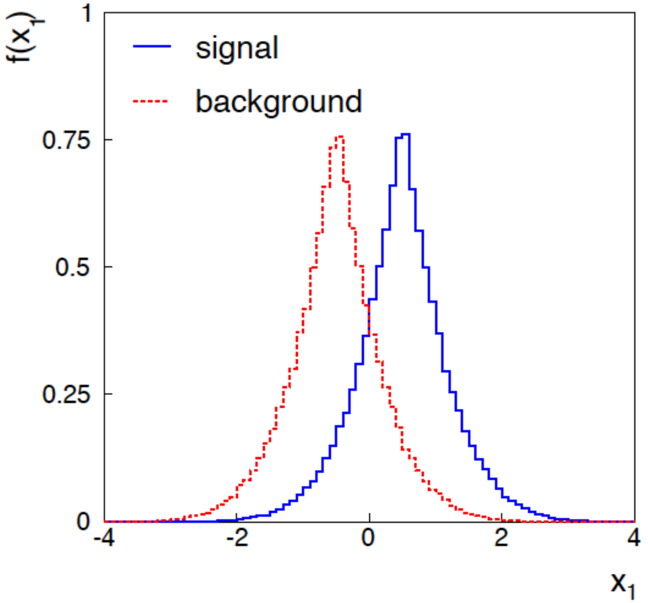
$$f(x_1, x_2|\mathrm{b}) = \frac{1}{\sqrt{2\pi}\sigma(x_2)} e^{-(x_1-\mu_\mathrm{b})^2/2\sigma^2(x_2)}\, \frac{1}{\lambda} e^{-x_2/\lambda}$$

$$\sigma(x_2) = \sigma_0 e^{-x_2/\xi}$$

Joint and marginal distributions of x_1, x_2







Distribution $f(x_2)$ same for s, b.

So does x_2 help discriminate between the two event types?

Likelihood ratio for 2D example

Neyman-Pearson lemma says best critical region is determined by the likelihood ratio:

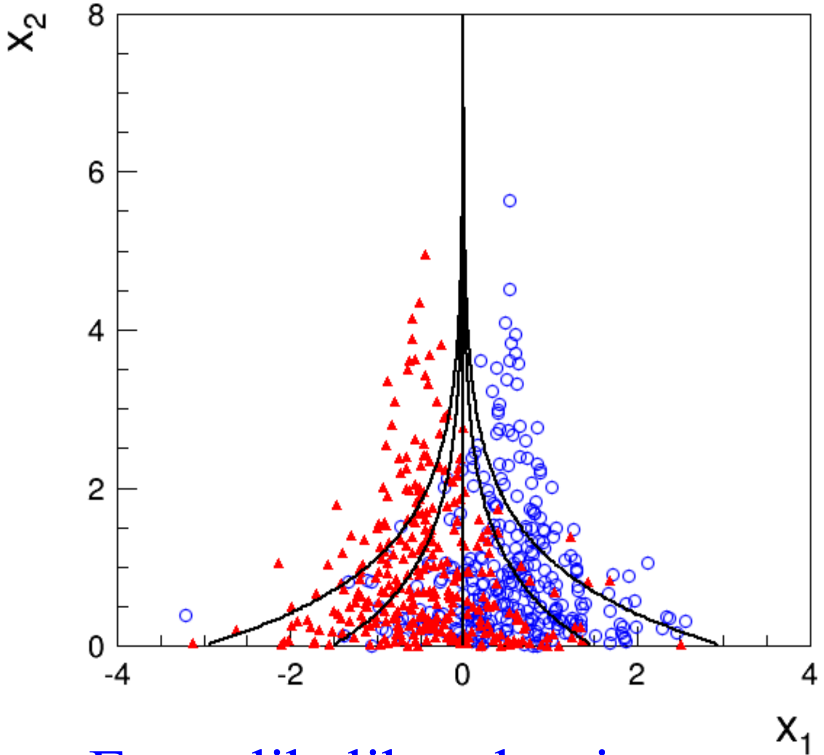
$$t(x_1, x_2) = \frac{f(x_1, x_2|\mathrm{s})}{f(x_1, x_2|\mathrm{b})}$$

Equivalently we can use any monotonic function of this as a test statistic, e.g.,

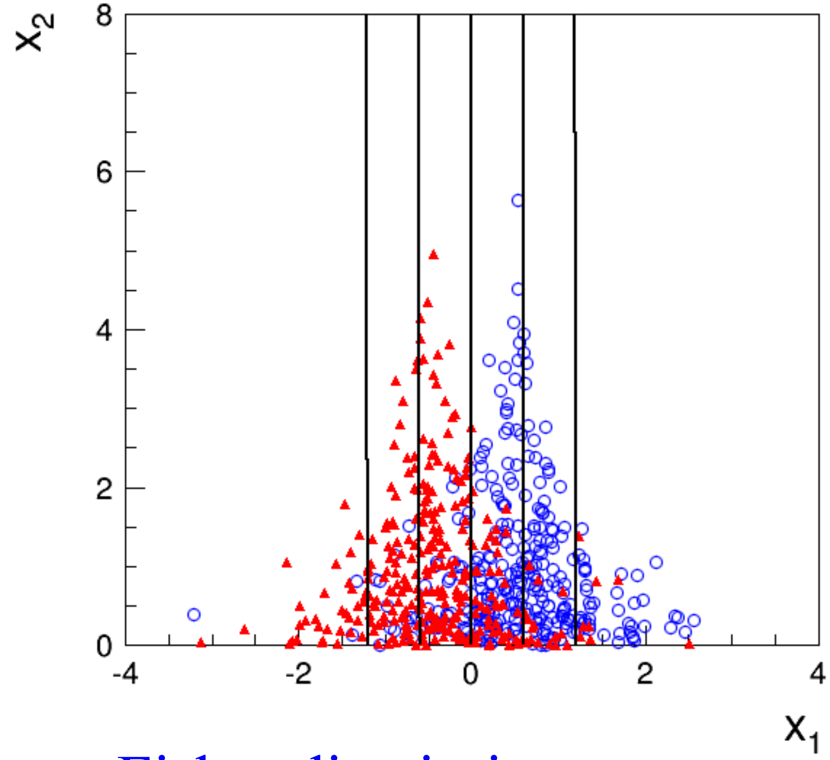
$$\ln t = \frac{\frac{1}{2}(\mu_\mathrm{b}^2 - \mu_\mathrm{s}^2) + (\mu_\mathrm{s} - \mu_\mathrm{b})x_1}{\sigma_0^2 e^{-2x_2/\xi}}$$

Boundary of optimal critical region will be curve of constant ln t, and this depends on x_2!

Contours of constant MVA output

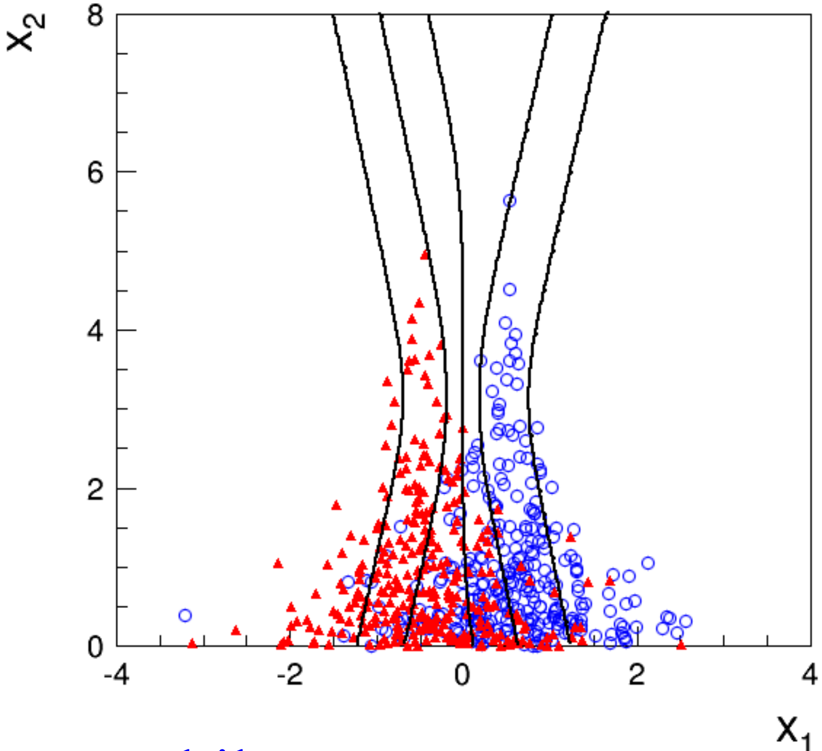


Exact likelihood ratio

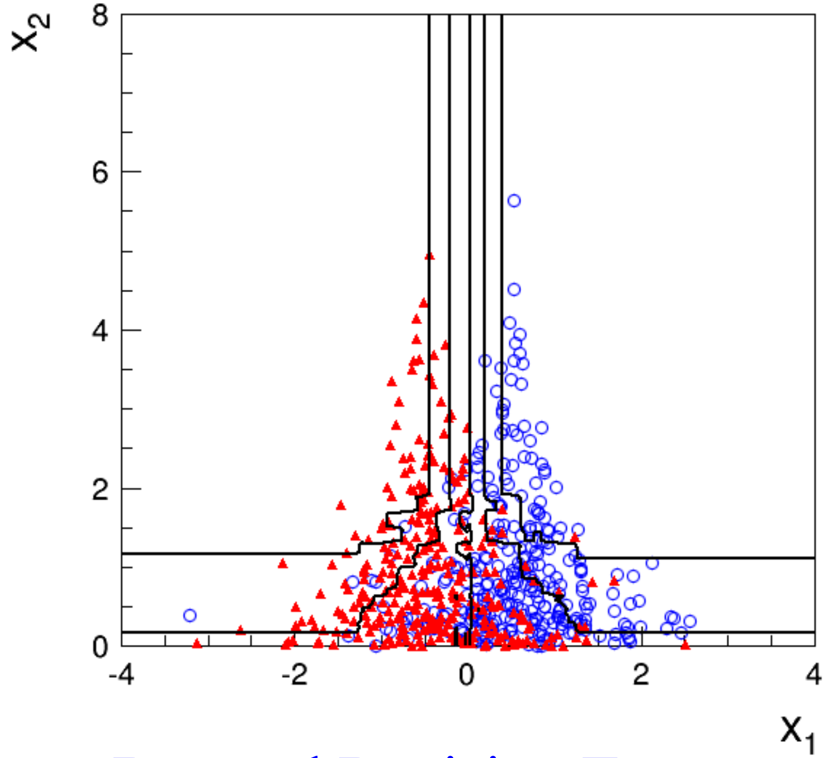


Fisher discriminant

Contours of constant MVA output



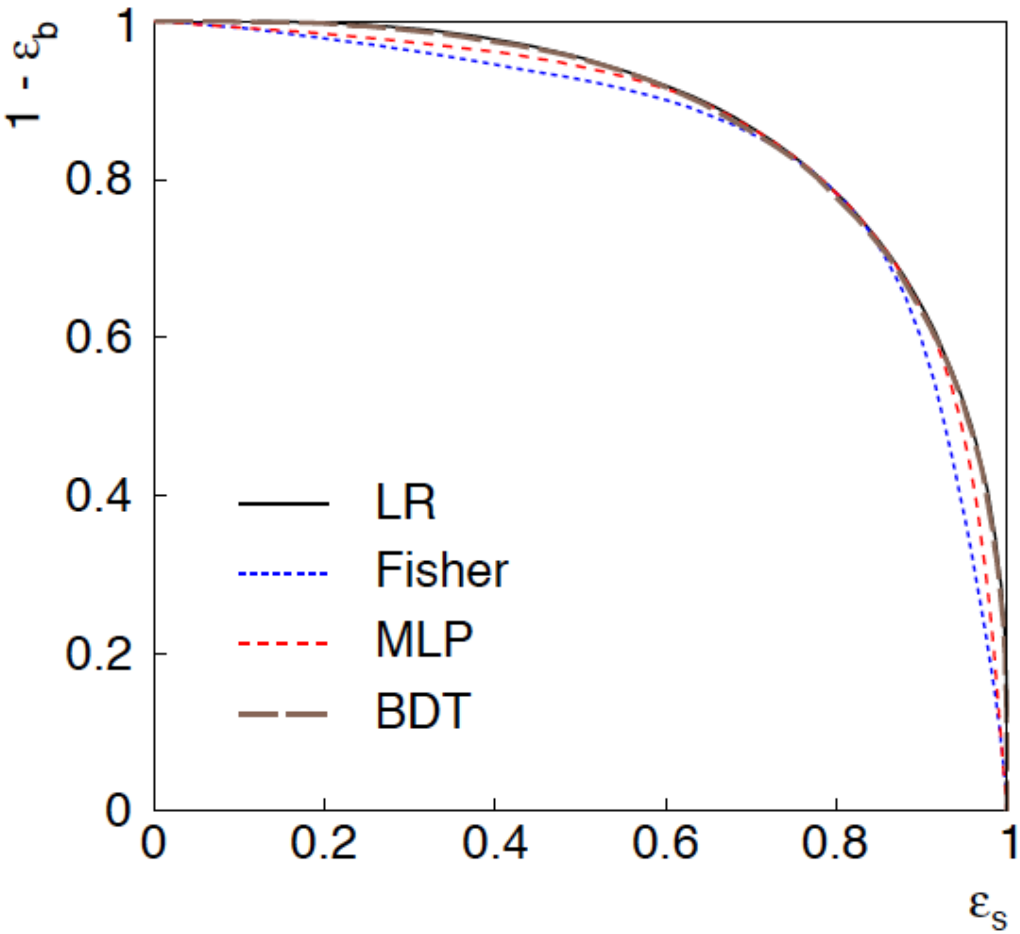
Multilayer Perceptron
1 hidden layer with 2 nodes



Boosted Decision Tree
200 iterations (AdaBoost)

Training samples: 10^5 signal and 10^5 background events

ROC curve



ROC = "receiver operating characteristic" (term from signal processing).

Shows (usually) background rejection ($1-\varepsilon_b$) versus signal efficiency ε_s.

Higher curve is better; usually analysis focused on a small part of the curve.

2D Example: discussion

Even though the distribution of x_2 is same for signal and background, x_1 and x_2 are not independent, so using x_2 as an input variable helps.

Here we can understand why: high values of x_2 correspond to a smaller σ for the Gaussian of x_1. So high x_2 means that the value of x_1 was well measured.

If we don't consider x_2, then all of the x_1 measurements are lumped together. Those with large σ (low x_2) "pollute" the well measured events with low σ (high x_2).

Often in HEP there may be variables that are characteristic of how well measured an event is (region of detector, number of pile-up vertices,...). Including these variables in a multivariate analysis preserves the information carried by the well-measured events, leading to improved performance.